Field Effect Transistor - Dual, N-Channel, Enhancement Mode

NDC7002N

General Description

These dual N-Channel enhancement mode power field effect transistors are produced using ON Semiconductor's proprietary, high cell density, DMOS technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. These devices is particularly suited for low voltage applications requiring a low current high side switch.

Features

- 0.51 A, 50 V, $R_{DS(ON)} = 2 \Omega$ @ $V_{GS} = 10 \text{ V}$
- High Density Cell Design for Low R_{DS(ON)}
- Proprietary SUPERSOT[™] -6 Package Design Using Copper Lead Frame for Superior Thermal and Electrical Capabilities
- High Saturation Current
- This is a Pb-Free Device



ON Semiconductor®

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TSOT23 6-Lead CASE 419BL

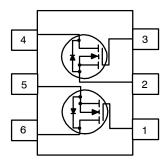
MARKING DIAGRAM



XXX = Specific Device Code
&E = Space Designator
&Y = Year of Production
&. = Pin One Identifier

= Pb-Free Package

PINOUT



SOT-6 (SUPERSOT™-6)

ORDERING INFORMATION

Device	Package	Shipping [†]	
NDC7002N	TSOT-23-6 (Pb-free)	3000 / Tape & Reel	

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Ratings	Units
V_{DS}	Drain-Source Voltage	50	V
V_{GSS}	Gate-Source Voltage	20	V
I _D	Drain Current - Continuous (Note 1a) - Pulsed	0.51 1.5	А
P _D	Power Dissipation (Note 1a) (Note 1b) (Note 1c)	0.96 0.9 0.7	W
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Units
Rejc	Thermal Resistance, Junction to Case (Note 1)	60	°C/W
Rеja	Thermal Resistance, Junction to Ambient (Note 1a)	130	

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

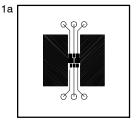
Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
OFF CHA	ARACTERISTICS	•			•	•	
BV _{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		50			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 40 V, V _{GS} = 0 V	T _J = 125°C			1 500	μА
I _{GSSF}	Gate-Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHA	RACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	T _J = 125°C	1 0.8	1.9 1.5	2.5 2.2	V
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 0.51 A	T _J = 125°C		1 1.7	2 3.5	Ω
		V _{GS} = 4.5 V, I _D = 0.35 A			1.6	4	
I _{D(on)}	On-State Drain Current	V _{GS} = 10 V, V _{DS} = 10 V		1.5			Α
9 _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 0.51 A			400		mS
DYNAMIC	C CHARACTERISTICS	•					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,			20		pF
Coss	Output Capacitance	f = 1.0 MHz			13		pF
C _{rss}	Reverse Transfer Capacitance				5		pF
SWITCH	ING CHARACTERISTICS (Note 2)						
t _{d(on)}	Turn-On Delay Time	V _{DD} = 25 V, I _D = 0.25 A,			6	20	ns
t _r	Turn-On Time	V_{GS} = 10 V, R_{GEN} = 25 Ω			6	20	
t _{d(off)}	Turn-Off Delay Time				11	20	
t _f	Turn-Off Fall Time				5	20	
Qg	Total Gate Charge	V _{DS} = 25 V, I _D = 0.51 A,			1		nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			0.19		nC
Q_{gd}	Gate to Drain Charge				0.33		nC
DRAIN-S	SOURCE DIODE CHARACTERISTICS						
IS	Maximum Continuous Source Current					0.51	Α
I _{SM}	Maximum Pulse Source Current (Note 2	te 2)				1.5	Α
V_{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 0.51 A (Note 2)			0.8	1.2	V

 $R_{\theta JA} \text{ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. } R_{\theta JC} \text{ is guaranteed by design while } R_{\theta CA} \text{ is determined by the user's board design.}$ $P_D(t) = \frac{T_J - T_A}{R_{\theta JA}(t)} = \frac{T_J - T_A}{R_{\theta JC} + R_{\theta CA}(t)} = I_D^2(t) \times R_{DS(ON)} @T_J$

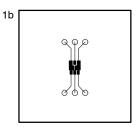
$$P_{D}(t) = \frac{T_{J} - T_{A}}{R_{\theta JA}(t)} = \frac{T_{J} - T_{A}}{R_{\theta JC} + R_{\theta CA}(t)} = I_{D}^{2}(t) \times R_{DS(ON)}@T_{CA}$$

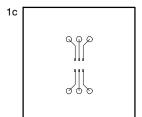
Typical R_{0JA} for single device operation using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- a. 130°C/W when mounted on a 0.125 in² pad of 2oz cpper.
- b. 140°C/W when mounted on a 0.005 in² pad of 2oz cpper.
- c. 180°C/W when mounted on a 0.0015 in² pad of 2oz cpper.



Scale 1:1 on letter size paper





2. Pulse Test: Pulse Width \leq 300 $\mu s,$ Duty cycle \leq 2.0 %.

TYPICAL ELECTRICAL CHARACTERISTICS

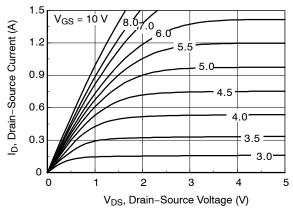


Figure 1. On-Region Characteristics

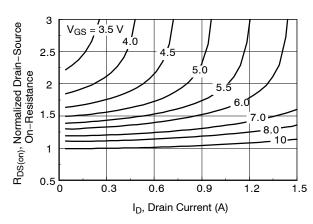


Figure 2. On-Resistance Variation with Gate Voltage and Current

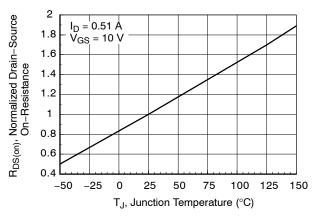


Figure 3. On-Resistance Variation with Temperature

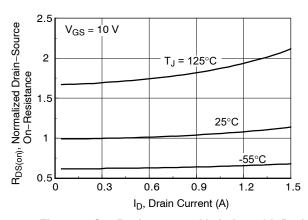


Figure 4. On–Resistance vs Variation with Drain Current and Temperature

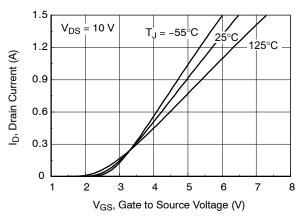


Figure 5. Transfer Characteristics

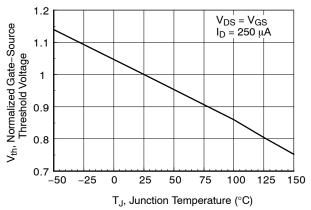


Figure 6. Gate Threshold Variation with Temperature

TYPICAL ELECTRICAL CHARACTERISTICS (continued)

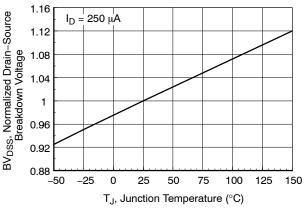


Figure 7. Breakdown Voltage Variation with Temperature

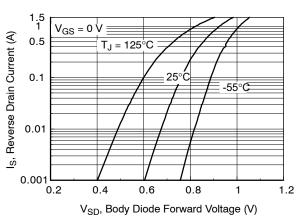


Figure 8. Body Diode Forward Voltage Variation with Current and Temperature

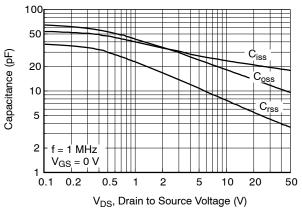


Figure 9. Capacitance Characteristics

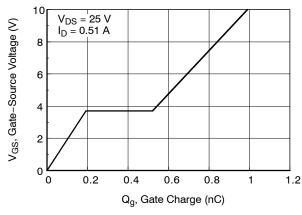


Figure 10. Gate Charge Characteristics

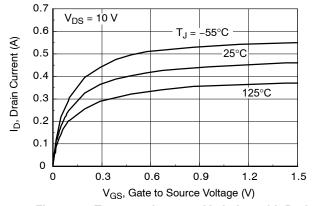


Figure 11. Transconductance Variation with Drain Current and Temperature

TYPICAL THERMAL CHARACTERISTICS

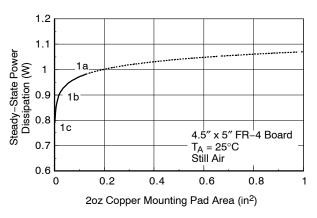


Figure 12. SOT-6 Dual Package Maximum Steady-State Power Dissipation versus Copper Mounting Pad Area

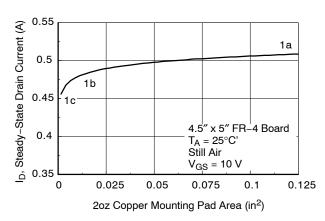


Figure 13. Maximum Steady-State Drain Current versus Copper Mounting Pad Area

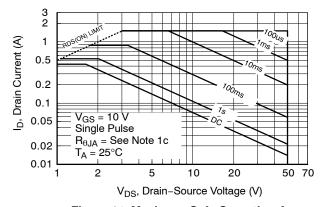


Figure 14. Maximum Safe Operating Area

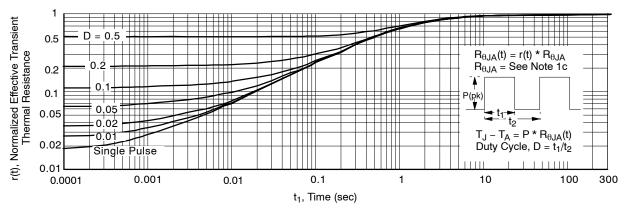


Figure 15. Transient Thermal Response Curve

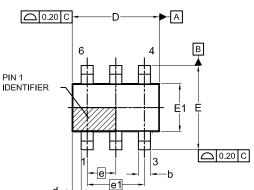
(Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.)

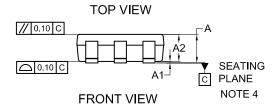
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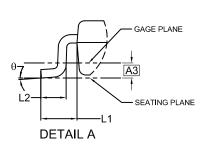


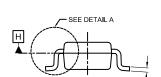
TSOT23 6-Lead CASE 419BL **ISSUE A**

DATE 31 AUG 2020









SIDE VIEW

03/1414

SYMM
Ę
0.95
1.00 MIN
2.60
0.70 MIN

LAND PATTERN RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: MILLIMETERS
 DIMENSIONS D AND E1 DO NOT INCLUDE MOLD FLASH,
 PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.25MM PER END. DIMENSIONS D AND E1 ARE DETERMINED AT DATUM H.
- 4. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

οιм	MILLIMETERS			
D,101	MIN.	NOM.	MAX.	
Α	0.90	1.00	1.10	
A1	0.00	0.05	0.10	
A2	0.70	0.85	1.00	
A3	0.25 BSC			
b	0.25	0.38	0.50	
С	0.10	0.18	0.26	
D	2.80	2.95	3.10	
d	0.30 REF			
Е	2.50	2.75	3.00	
E1	1.30	1.50	1.70	
е	0.95 BSC			
e1	1.90 BSC			
L1	0.60 REF			
L2	0.20	0.40	0.60	
θ	0°		10°	

GENERIC MARKING DIAGRAM*



XXX = Specific Device Code

= Date Code Μ

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present. Some products may not follow the Generic Marking.

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